

RoH9

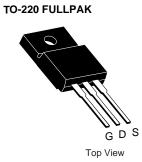
COMPLIANT

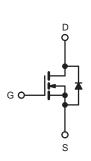
K960-VB Datasheet **Power MOSFET**

PRODUCT SUMMA	RY	
V _{DS} (V)	950)
R _{DS(on)} (Ω)	$V_{GS} = 10 V$	2.4
Q _g (Max.) (nC)	28	3
Q _{gs} (nC)	5	
Q _{gd} (nC)	12	2
Configuration	Sing	le

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC





N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C	= 25 °C, unle	ess otherwis	se noted)		
PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V _{DS}	950	V
Gate-Source Voltage			V _{GS}	± 20	v
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	1_	6	
Continuous Brain Current	VGS at TO V	T _C = 100 °C	I _D	3.9	A
Pulsed Drain Current ^a			I _{DM}	24	
Linear Derating Factor				1.5	W/°C
Single Pulse Avalanche Energy ^b			E _{AS}	770	mJ
Repetitive Avalanche Current ^a			I _{AR}	7.8	A
Repetitive Avalanche Energy ^a			E _{AR}	19	mJ
Maximum Power Dissipation	T _C =	25 °C	PD	190	W
Peak Diode Recovery dV/dt ^c	•		dV/dt	5.0	V/ns
Operating Junction and Storage Temperature Rang	le		T _J , T _{stg}	- 55 to + 150	°C
Soldering Recommendations (Peak Temperature)	for 1	0 s		300 ^d	
Mounting Torque	6-32 or M3 screw			10	lbf ∙ in
Mounting Torque	0-32 OF IV	IS SCIEW	Ē	1.1	N · m

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD} = 50$ V, starting $T_J = 25$ °C, L = 23 mH, $R_g = 25 \Omega$, $I_{AS} = 7.8$ A (see fig. 12). c. $I_{SD} \le 7.8$ A, dl/dt ≤ 140 A/µs, $V_{DD} \le 600$ V, $T_J \le 150$ °C. d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

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THERMAL RESISTANCE RATI	NGS							
PARAMETER	SYMBOL	TYP. MAX.			UNIT			
Maximum Junction-to-Ambient	R _{thJA}	-		40				
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24 -			°C/W			
Maximum Junction-to-Case (Drain)	R _{thJC}	- 0.65						
SPECIFICATIONS (T _J = 25 °C, u	nless otherwi	se noted)						
PARAMETER	SYMBOL	1		IONS	MIN.	TYP.	MAX.	UNIT
Static						1	[
Drain-Source Breakdown Voltage	V _{DS}	V _{GS}	= 0 V, I _D = 2	250 µA	950	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$		e to 25 °C,		-	0.98	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}		= V _{GS} , I _D =		2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		$V_{GS} = \pm 20$		-	-	± 100	nA
Ű			= 800 V, V _G		-	-	1	
Zero Gate Voltage Drain Current	I _{DSS}			/, T _J = 125 °C	-	-	45	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	1		-	2.4	_	Ω
Forward Transconductance			= 100 V, I _D =		4.5	-	-	S
Dynamic								L
Input Capacitance	C _{iss}	V _{GS} = 0 V,		-	816	-		
Output Capacitance	C _{oss}		V _{DS} = 25 \	Ι,	-	68	-	pF
Reverse Transfer Capacitance	C _{rss}	f = 1	.0 MHz, se	e fig. 5	-	17	-	
Total Gate Charge	Qg				-	-	28	
Gate-Source Charge	Q _{gs}			A, $V_{DS} = 400 V$, ig. 6 and 13^{b}	-	-	5	nC
Gate-Drain Charge	Q _{gd}		300 11		-	-	12	1
Turn-On Delay Time	t _{d(on)}		•		-	15	-	
Rise Time	t _r	$V_{DD} = 400 \text{ V}, \text{ I}_{D} = 3.8 \text{ A}, \\ \text{R}_{g} = 6.2 \ \Omega, \text{ R}_{D} = 52 \ \Omega \\ \text{see fig. } 10^{\text{b}}$		-	27	-	ns	
Turn-Off Delay Time	t _{d(off)}			-	66	-		
Fall Time	t _f			-	30	-		
Internal Drain Inductance	L _D	Between lead 6 mm (0.25") 1	from		-	5.0	-	
Internal Source Inductance	L _S	die contact		-	13	-	nH	
Drain-Source Body Diode Characteristic	s							
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	5.0	A	
Pulsed Diode Forward Current ^a	I _{SM}			-	-	21		
Body Diode Voltage	V_{SD}	T _J = 25 °C	C, I _S = 3.8 A	, V _{GS} = 0 V ^b	-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	T,1 =	25 °C, I _F =	3.8 A,	-	320		ns
Body Diode Reverse Recovery Charge	Q _{rr}		/dt = 100 A		-	3.3		μC
Forward Turn-On Time	t _{on}	Intrinsic tu	rn-on time	is negligible (turn	-on is doi	ninated b	by L _S and	L _D)

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 µs; duty cycle ≤ 2 %.

K960-VB



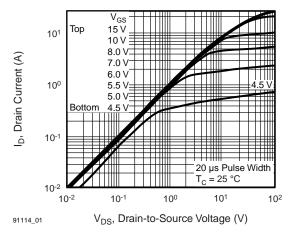


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

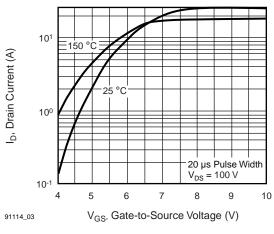


Fig. 3 - Typical Transfer Characteristics

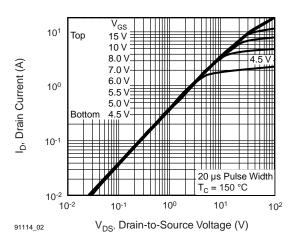


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

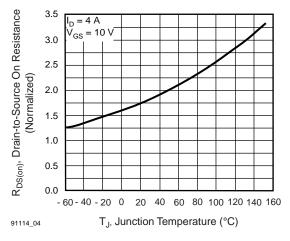


Fig. 4 - Normalized On-Resistance vs. Temperature



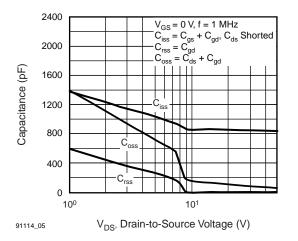


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

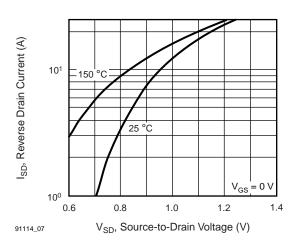


Fig. 7 - Typical Source-Drain Diode Forward Voltage

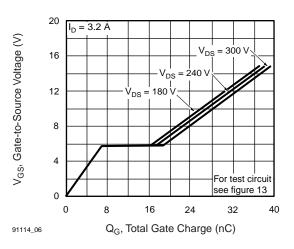


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

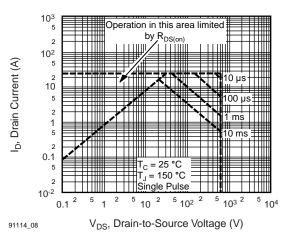


Fig. 8 - Maximum Safe Operating Area



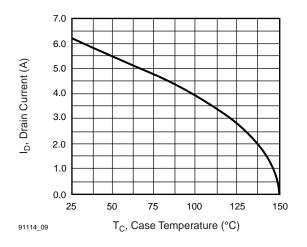


Fig. 9 - Maximum Drain Current vs. Case Temperature

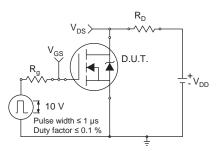


Fig. 10a - Switching Time Test Circuit

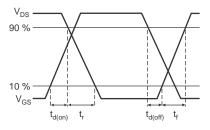


Fig. 10b - Switching Time Waveforms

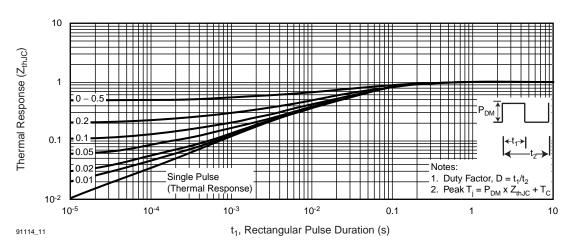


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



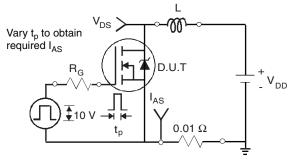


Fig. 12a - Unclamped Inductive Test Circuit

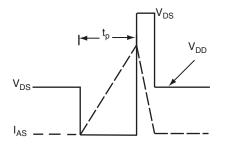


Fig. 12b - Unclamped Inductive Waveforms

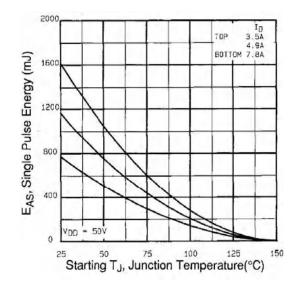


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

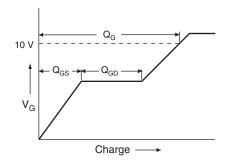
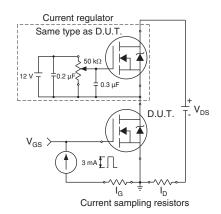


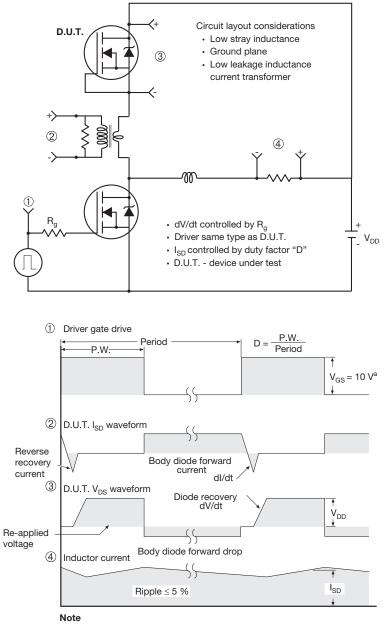
Fig. 13a - Basic Gate Charge Waveform







Peak Diode Recovery dV/dt Test Circuit

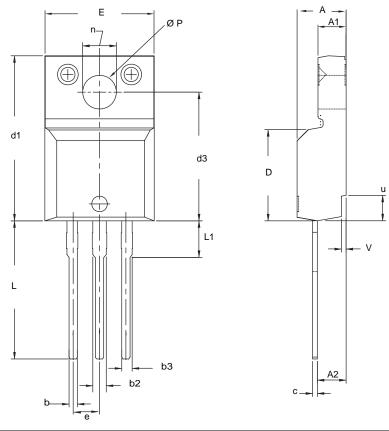


a. $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel



TO-220 FULLPAK (HIGH VOLTAGE)



	MILLI	METERS	INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.570	4.830	0.180	0.190	
A1	2.570	2.830	0.101	0.111	
A2	2.510	2.850	0.099	0.112	
b	0.622	0.890	0.024	0.035	
b2	1.229	1.400	0.048	0.055	
b3	1.229	1.400	0.048	0.055	
С	0.440	0.629	0.017	0.025	
D	8.650	9.800	0.341	0.386	
d1	15.88	16.120	0.622	0.635	
d3	12.300	12.920	0.484	0.509	
E	10.360	10.630	0.408	0.419	
е	2.54	BSC	0.100	BSC	
L	13.200	13.730	0.520	0.541	
L1	3.100	3.500	0.122	0.138	
n	6.050	6.150	0.238	0.242	
ØP	3.050	3.450	0.120	0.136	
u	2.400	2.500	0.094	0.098	
V	0.400	0.500	0.016	0.020	

Notes

1. To be used only for process drawing. 2. These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads. 3. All critical dimensions should C meet $C_{pk} > 1.33$. 4. All dimensions include burrs and plating thickness. 5. No chipping or package damage.



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